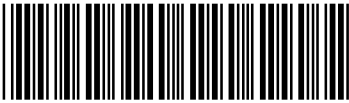


Search Notes

Application/Control No.

10/760,505

Examiner

LOIS ZHENG

Applicant(s)/Patent under
Reexamination

HIRAIWA ET AL.

Art Unit

1793

SEARCHED

Class	Subclass	Date	Examiner

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Inventorship search	3/13/2009	LLZ
Updated EAST Search	3/13/2009	LLZ